

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
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Examiner	Art Unit	
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SEARCHED

Class	Subclass	Date	Examiner
375	229, 232, 233, 234	4/3/2008	EB

SEARCH NOTES

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East	4/3/2008	EB

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
375	229, 233	4/3/2008	EB